



Attorney Docket: 3319.3A (02US2)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:

James W. Overbeck

Serial No:

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For:

WIDE FIELD OF VIEW AND HIGH SPEED SCANNING MICROSCOPY

Examiner: T.Q. Nguyen

Art Unit: 2872

COMMISSIONER FOR PATENTS WASHINGTON, D.C. 20231

Sir:

MISSIONER FOR PATENTS
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RESPONSE

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TECHNOLOGY CENTER 288

In response to the Communication mailed April 18, 2003, Applicant re-summits the Response mailed initially on April 2, 2003, now written in the "new" format. The claim changes are written to replace the Response filed on April 2, 2003 as follows: